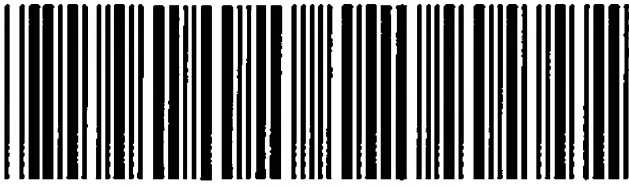


<b>Search Notes</b> 	<b>Application/Control No.</b>	<b>Applicant(s)/Patent under Reexamination</b>	
	10/634,351	LIN ET AL.	
	<b>Examiner</b>	<b>Art Unit</b>	
	Rip A. Lee	1713	

SEARCHED			
Class	Subclass	Date	Examiner
525	490	11-22-2005	RL
525	474	11-22-2005	RL
525	240	11-22-2005	RL

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST updated search	11-22-2005	RL